SHEET 1 OF 1

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.		SERIAL NO.				
(Modified)		PATENT AND TRAD	EMARK OFFICE	292393US2PCT		10/582,791				
				APPLICANT						
LIST OF	REFE	RENCES CITED BY APP	LICANT	Laurent PAIN						
				FILING DATE		GROUP				
				June 14, 2006						
				U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS				
/BT/	AA	2003 039923	02-27-03	MANGAT, Pawitter et al.						
	AB	6 596 465	07-22-03	MANGAT, Pawitter Jit Singh et al.						
	AC	2003 027053	02-06-03	YAN, Péi-yang						
	AD	2002 122995	09-05-02	MANCINI, David P. et al.						
	AE	5 945 238	08-31-99	HUGGINS, Alan H. et al.						
	AF	5 985 518	11-16-99	HUGGINS, Alan H. et al.						
/BT/	AG	5 953 577	09-14-99	HUGGINS, Alan H. et al.						
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/BT/	AO	60 142518	12-03-85	JP (with English abstract)			NO			
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		OTHER RE	FERENCES (Including Author, Title, Date, Pertinent	t Pages, ef	tc.)				
/DT/				used Ion Beam and Electron Beam Induc	ed Deposi	tion Proces	sses", Microelectron.			
/BT/	AW	Reltab., Vol. 36, No. 11	i/12, pgs. 1779	9-1782, 1996.						
/BT/	AX	WARD, B.W.et al.," Repair of Photomasks with Focussed Ion Beams", SPIE, Vol. 537, pgs. 110-116, 1985.								
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	AZ	Additional References sheet(s) attached								
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

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Form PTO 1449 (Modified)		DEPARTMENT	OMMERCE MARK OFFICE	ATTY DOCKET NO.	SERIAL NO.				
PADE			292393US2PCT	10/582,791					
	0555	PENCES SITED BY AL	OOL LOANIT	APPLICANT					
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS		FILING DATE IF APPROPRIATE	
/BT/	AA	4 751 169	06-14-88	BEHRINGER, Uwe et al.					
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	AZ				Addi	tional Refe	erences :	sheet(s) attached	
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